

Notice of References Cited	Application/Control No. 10/802,205	Applicant(s)/Patent Under Reexamination LEU ET AL.	
	Examiner Michael Aboagye	Art Unit 1725	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,463,197	10-1995	Miyazaki, Naoki	219/56.22
*	B	US-6,566,770	05-2003	Nakamura, Gen	307/154
*	C	US-4,485,957	12-1984	Sugimoto et al.	228/4.5
*	D	US-2002/0093130	07-2002	Behler et al.	269/21
*	E	US-7,064,289	06-2006	Schmidt et al.	219/99
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 03-015974	02-2003	germany	Schmidt et al.	B23K 9/20
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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